

DEVICE AND METHOD OF CORRECTING EXPOSURE DEFECTS IN
PHOTOLITHOGRAPHY

Hickman, Craig A.

Appl. No.: Unassigned Atty Docket: MICRON.100C1

1/5

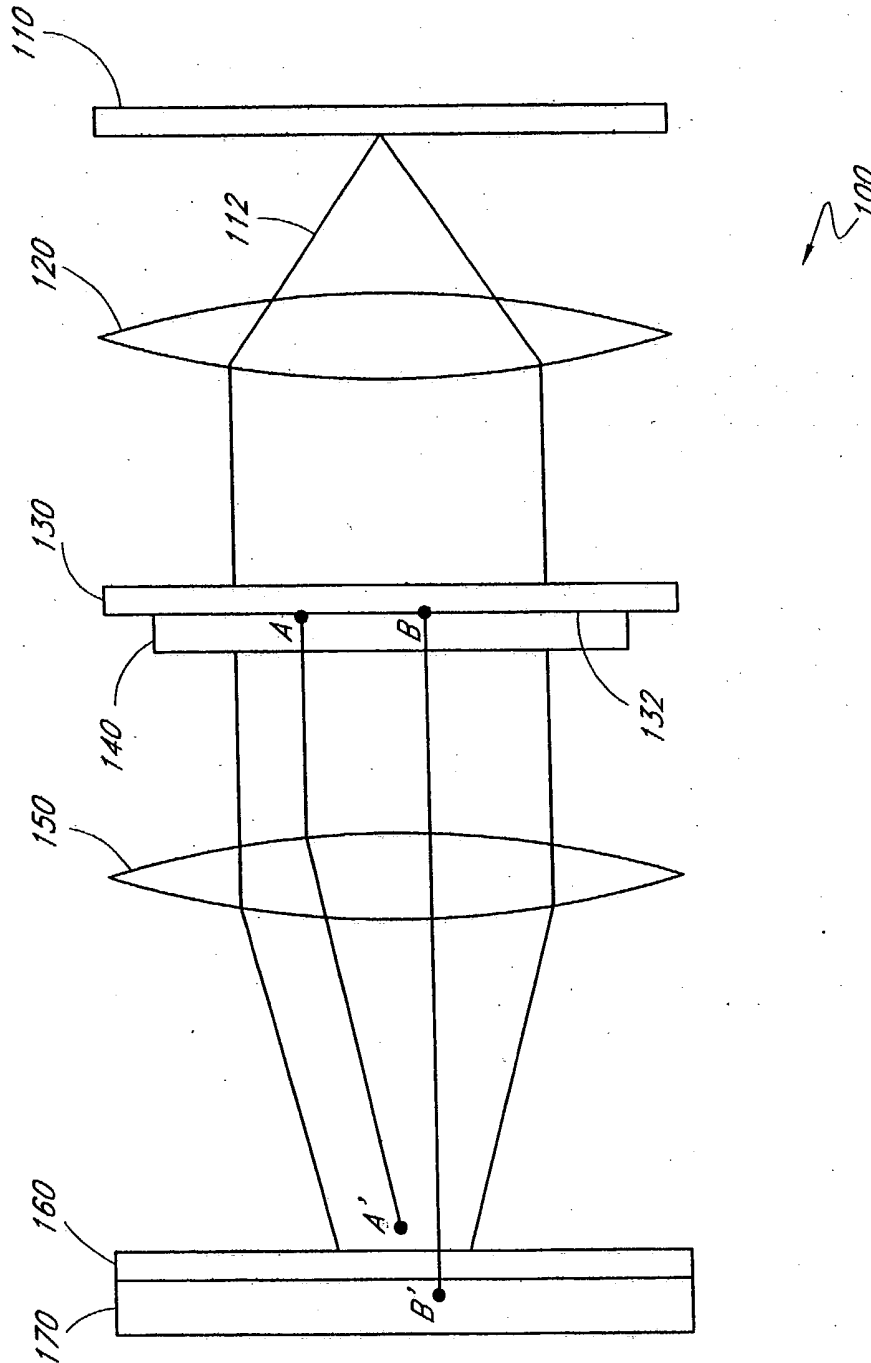


FIG. 1
(PRIOR ART)

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2/5

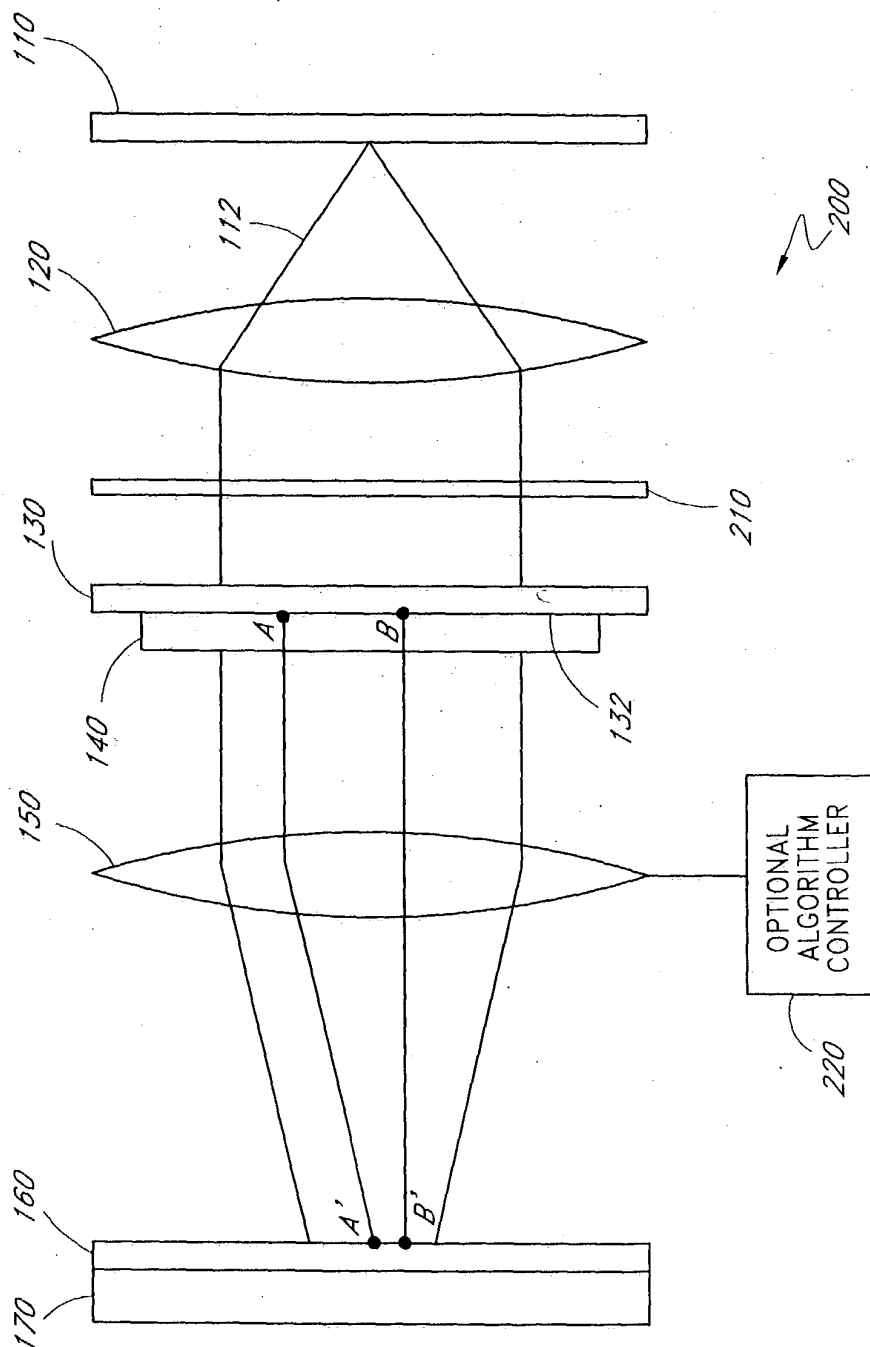


FIG. 2

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3/5

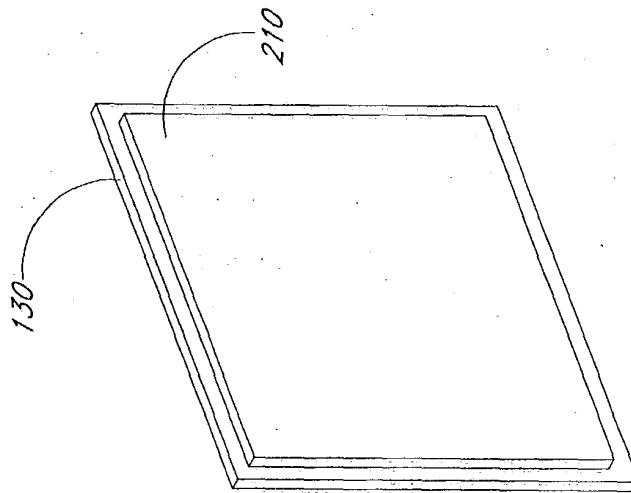


FIG. 3

4/5

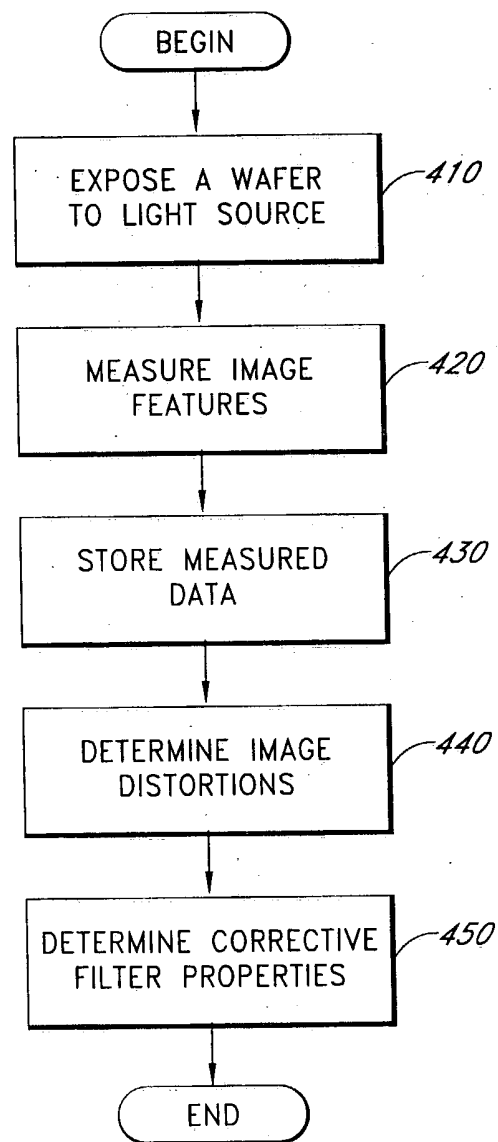


FIG. 4

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5/5

